

Introduction of a Space Glade Micro Processing Unit for Future Space Applications

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1. Background
2. Benchmarking
3. Device features
4. Target Specifications
5. Architecture
6. Operating System
7. Evaluation status
8. Development schedule

1. Background



- ✓ Space activities has started since 1955 in Japan. (2003 ~ JAXA)
 - ✓ About 35 types of rockets have been developed and launched. (More than 300 satellites)
 - ✓ EEE parts for space-use have been supporting to do space activity for a long time.



- H-2
- 1988 ~ 1999

Purely Domestic



- H-2A
- 2001 ~
- for almost satellites

Domestic & Overseas



- H-2B
- 2009 ~ 2020
- for cargo

Domestic & Overseas



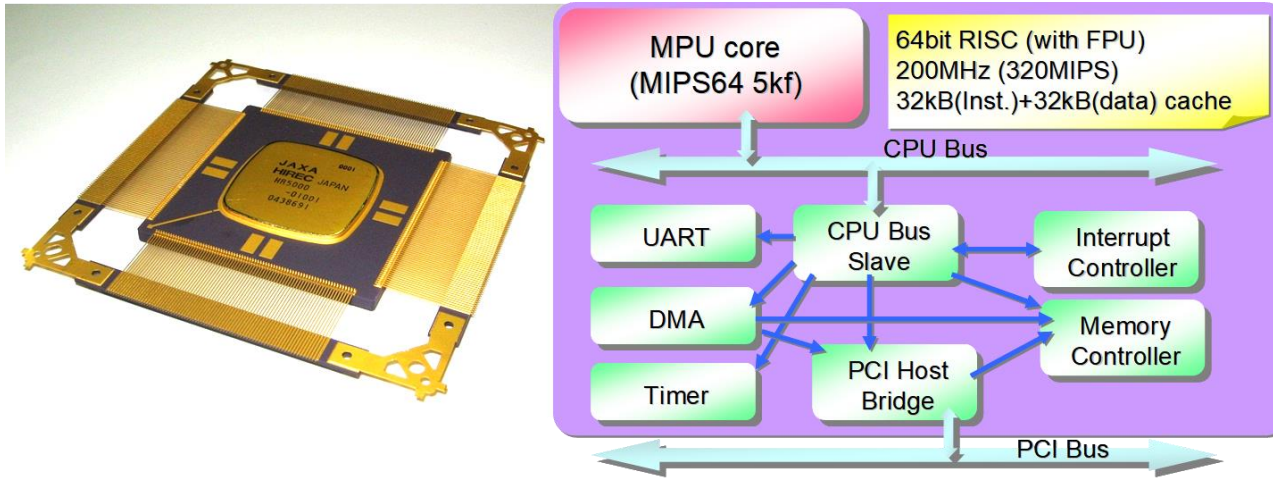
- H-3
- Under development

COTS-base

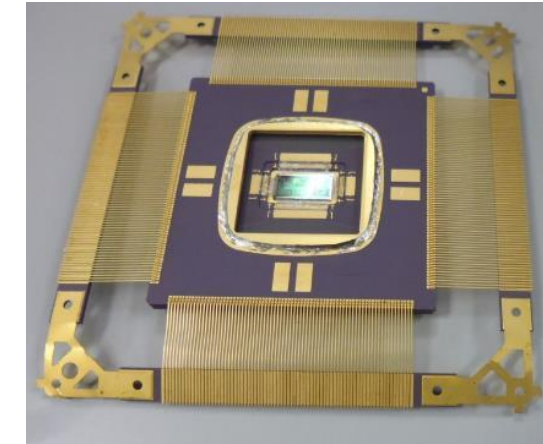
1. Background



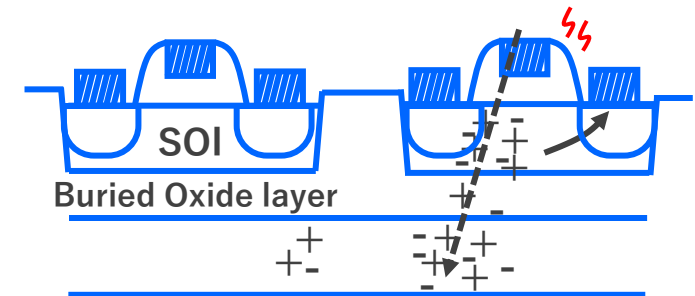
Current MPU: HR5000 (Bulk CMOS) and HR5000S (SOI)



SOI Process
0.15 μ m



- MIPS64 5kf architecture with on-chip peripherals.
- 0.18 μ m commercial CMOS process.
- 200MHz operation (320MIPS)
- JAXA qualified. (Mar. 2007)

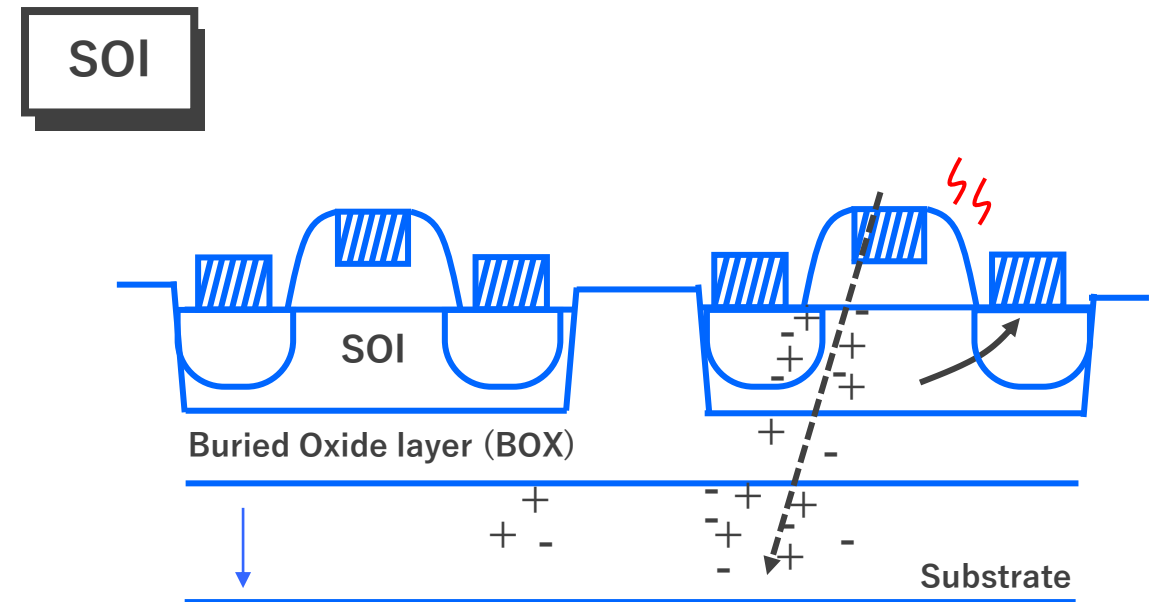
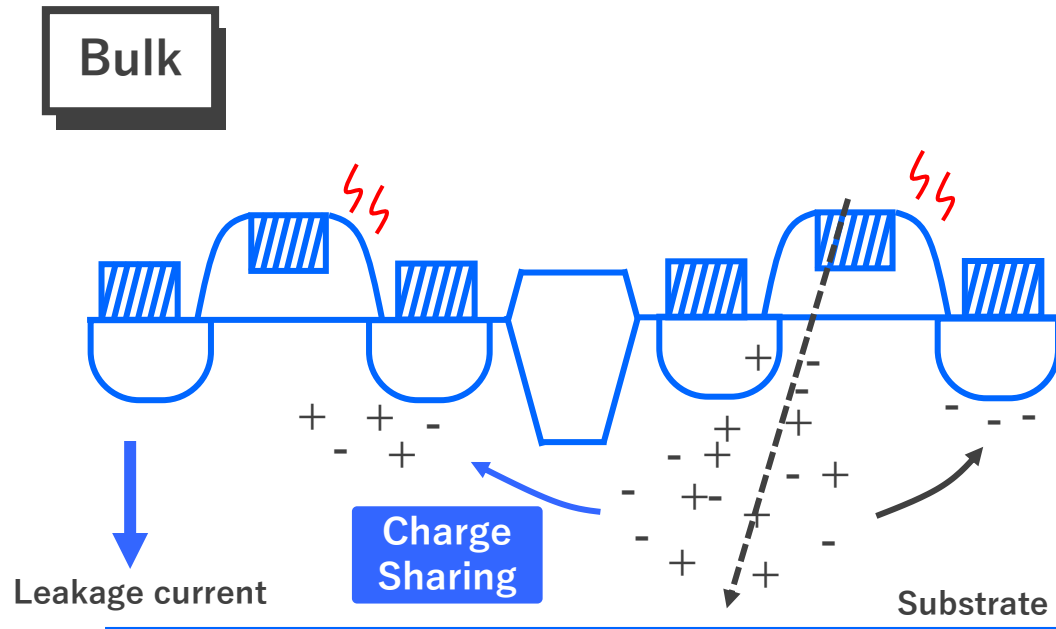


Conceptual drawing of SOI process

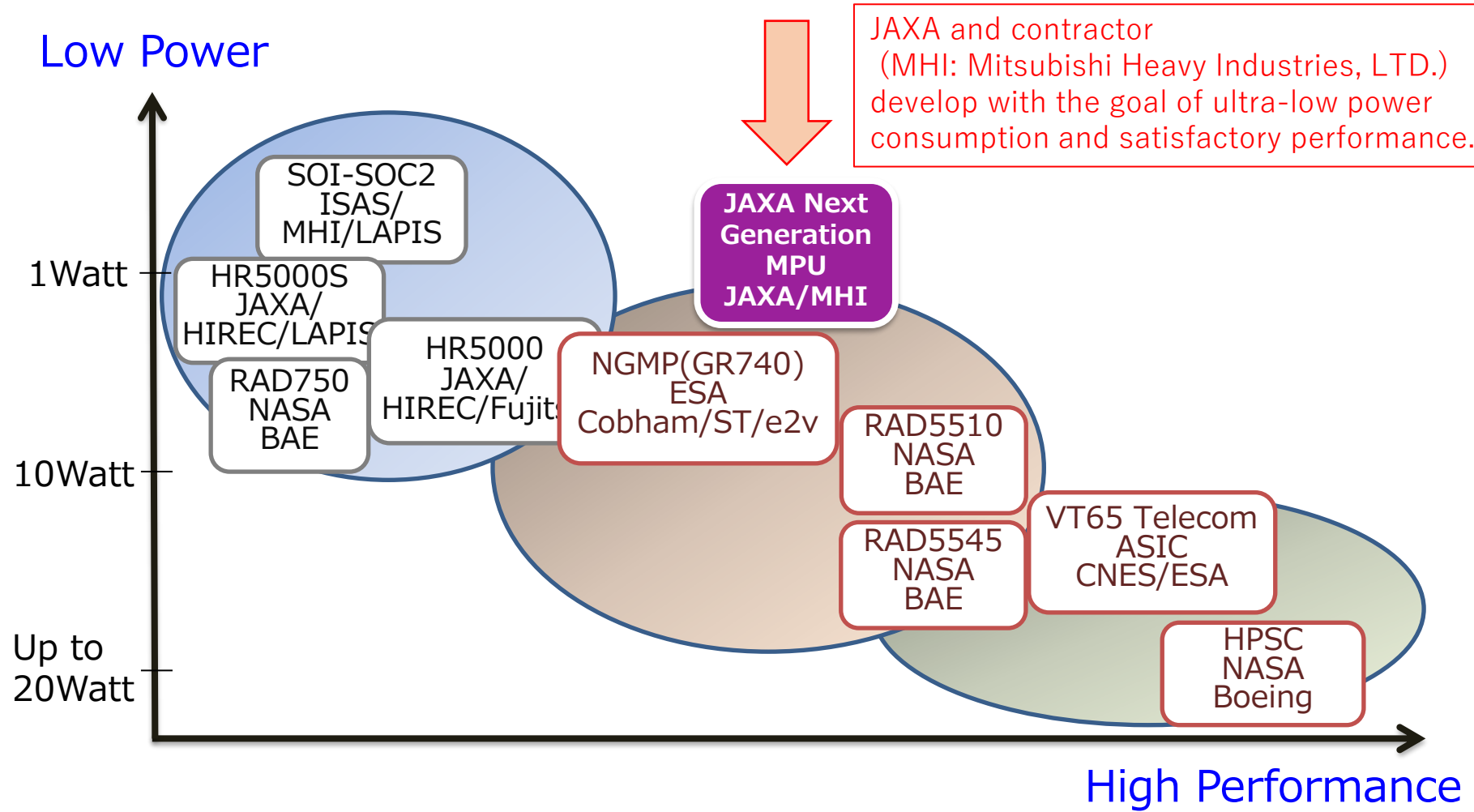
SOI technology is introduced to the MPU as a radiation hardening methodology

1. Background

The differences between Bulk process and SOI process



- Advantages of SOI process
 - Device structure of SOI process itself can prevent charge sharing effect → Good Radiation Tolerant
 - Leakage current can be well suppressed. → Low power consumption

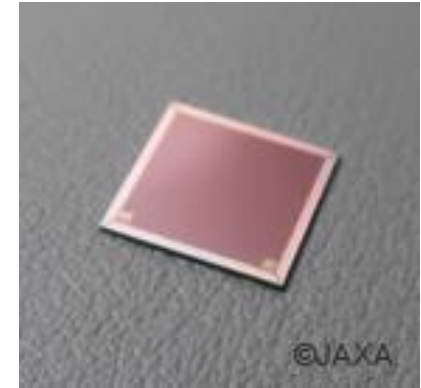


Position of JAXA Next Generation MPU in Global MPU Tendency

3. Device features of the next MPU



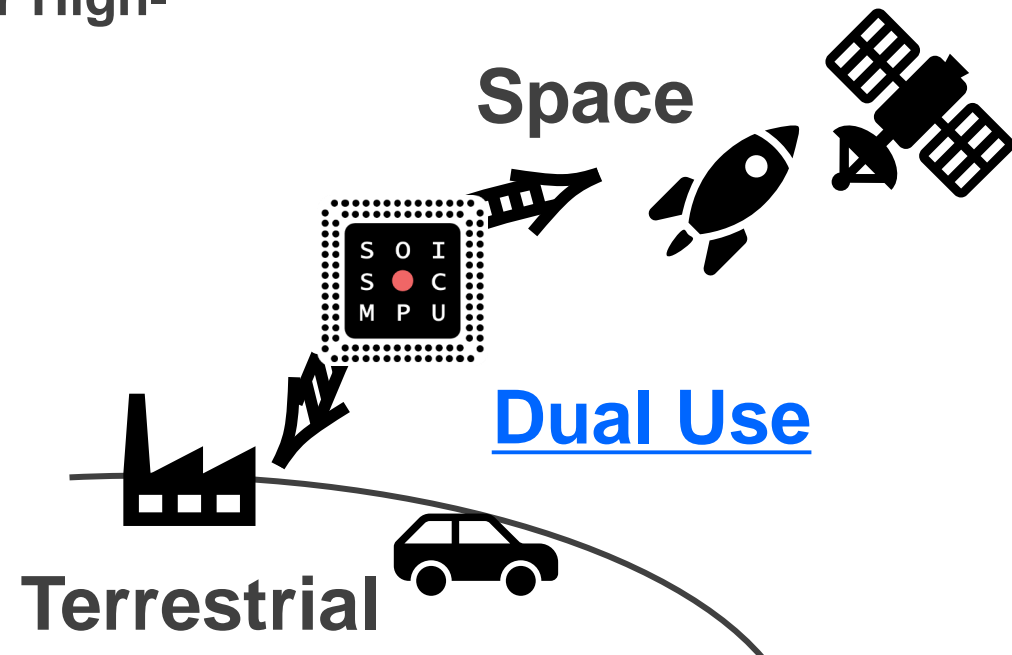
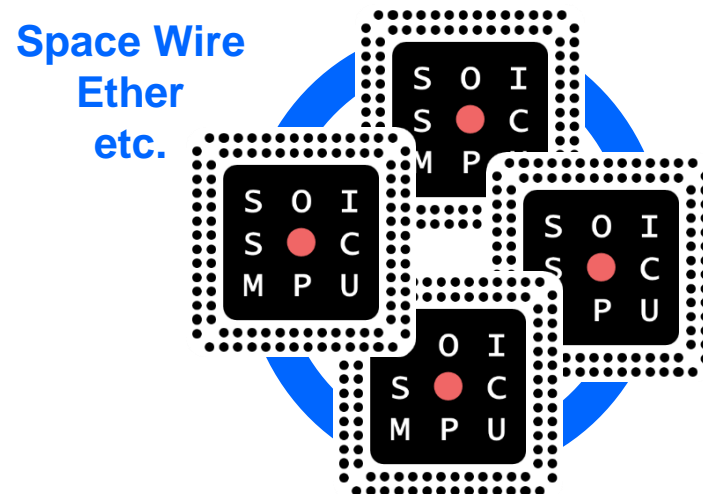
- ❑ Micro Processing Unit (MPU) for next decade
 - Dual Core processor (RXv3, Renesas Electronics)
 - A variety of Interface protocols (Space Wire, Ethernet,..etc)
 - High reliability as a space grade (JAXA-QTS-2010)
 - On-chip code memory (SRAM)
- ❑ Features
 - Low power consumption; SOI process
 - High Radiation tolerance
 - Cluster connection for High Availability (HA) and/or High-Performance Computing (HPC)



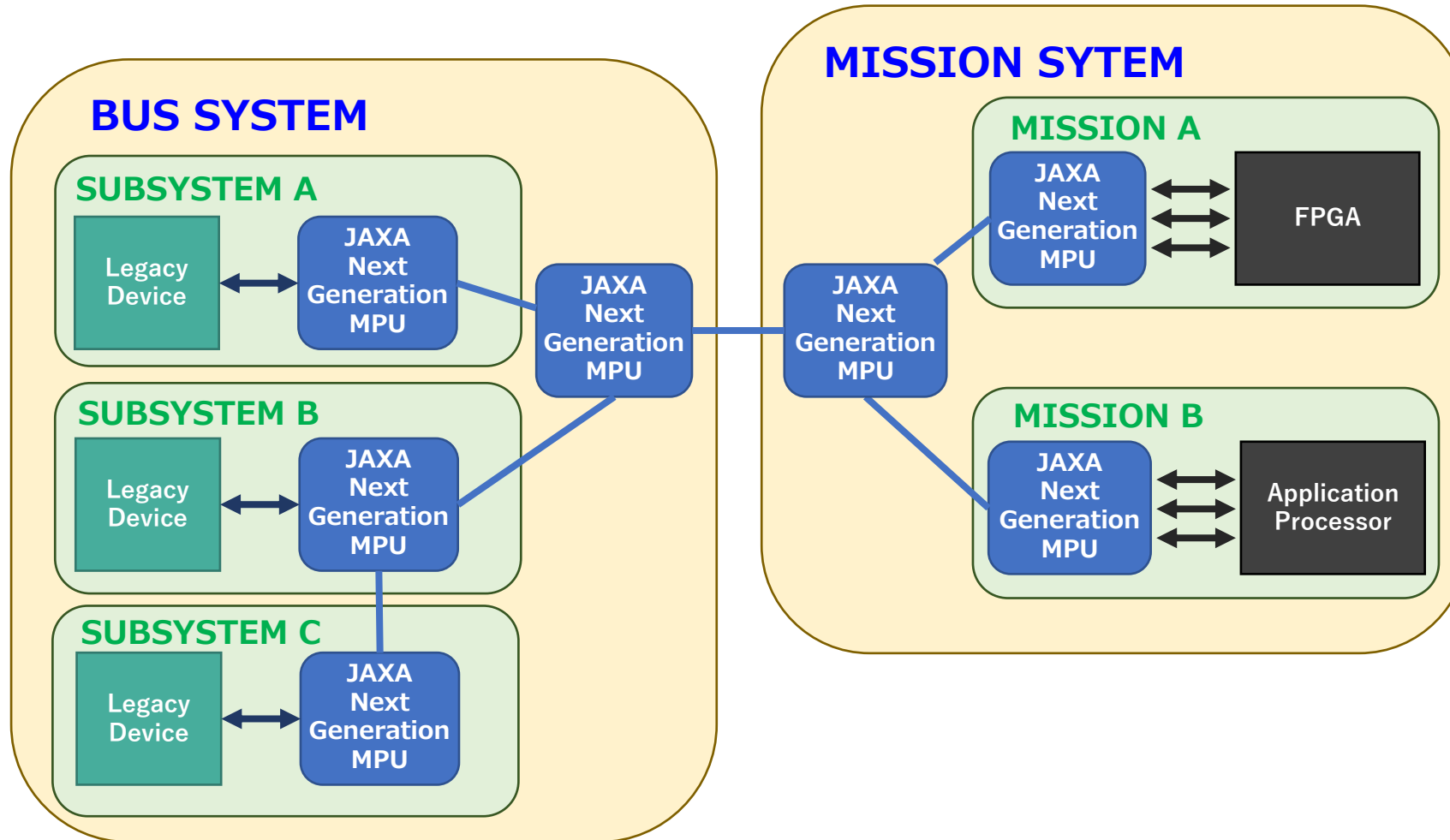
Engineering Model sample

Concept

- Dual Use
- Low power
- High reliability
- Middle performance
 - ➔ Cluster connection



3. Device features of the next MPU



Various I/Os widely support from legacy devices to future interfaces.
Network I/Os improve development efficiency by distributed system.

4. Target specifications



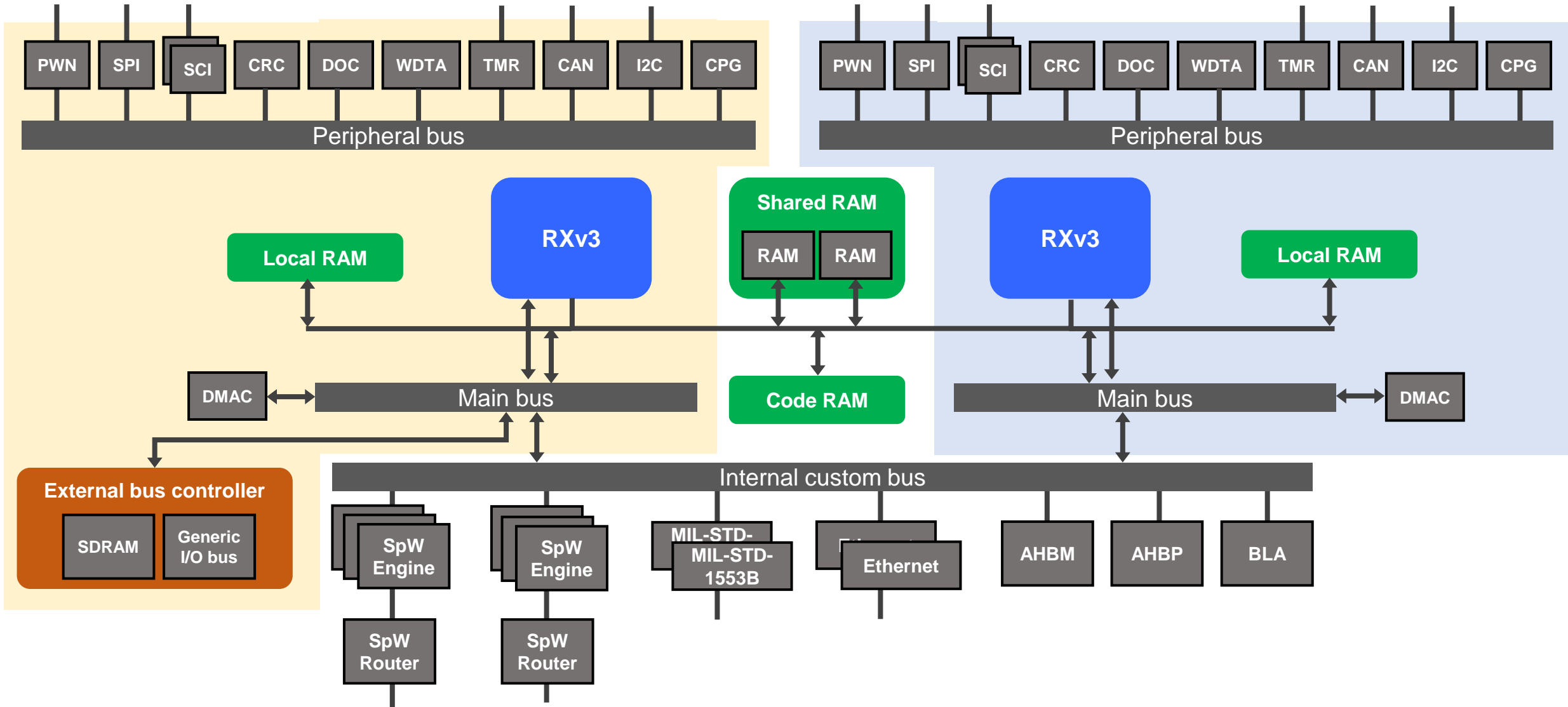
Architecture

SoC:
interfaces

Qualification &
Reliability

Function	Parameter	Description
Core & Memory	Dual Core (RVv3)	Double-precision floating point
	Frequency	250 MHz (900 CoreMark; 10x larger than that of current MPU) @PVT=Typical
	On-chip memory	HD-SRAM w/ EDAC <ul style="list-style-type: none"> • Instruction-RAM • Data-RAM RHBD-SRAM w/ EDAC <ul style="list-style-type: none"> • Data-RAM
	Power consumption	< 1 W @PVT=typical
Interface	Space Wire Driver	6 channels
	Ethernet	2 channels
	MIL-STD-1553B	2 channels
	CAN	2 channels
	SCI	4 channels
	SPI	2 channel
	I2C	2 channel
Hard-Macros	Security-IP	Elliptic Curve Cryptography
Qualification guideline		Target
JAXA-QTS-2010C		Specification for space grade LSI

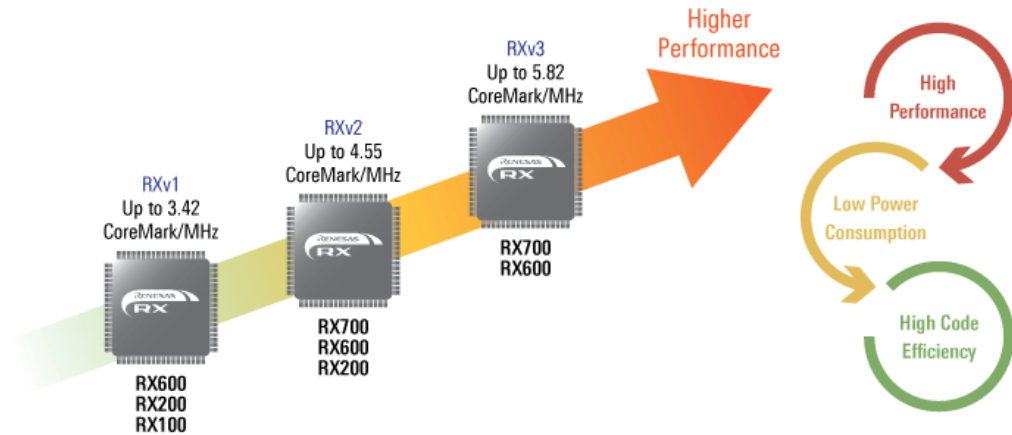
5. Device architecture (Function block diagram)



5. Device architecture (RXv3)



- ❑ RXv3-based Core architecture (We combined an FPU module with RXv3 architecture)
- ❑ One of the RX-series (Renesas) which is implemented into industry, commercial, etc.



- 32bit CISC Harvard Architecture
- 5-stage pipeline
- FPU
- Up to 6.01 Coremark/MHz
- Low power consumption

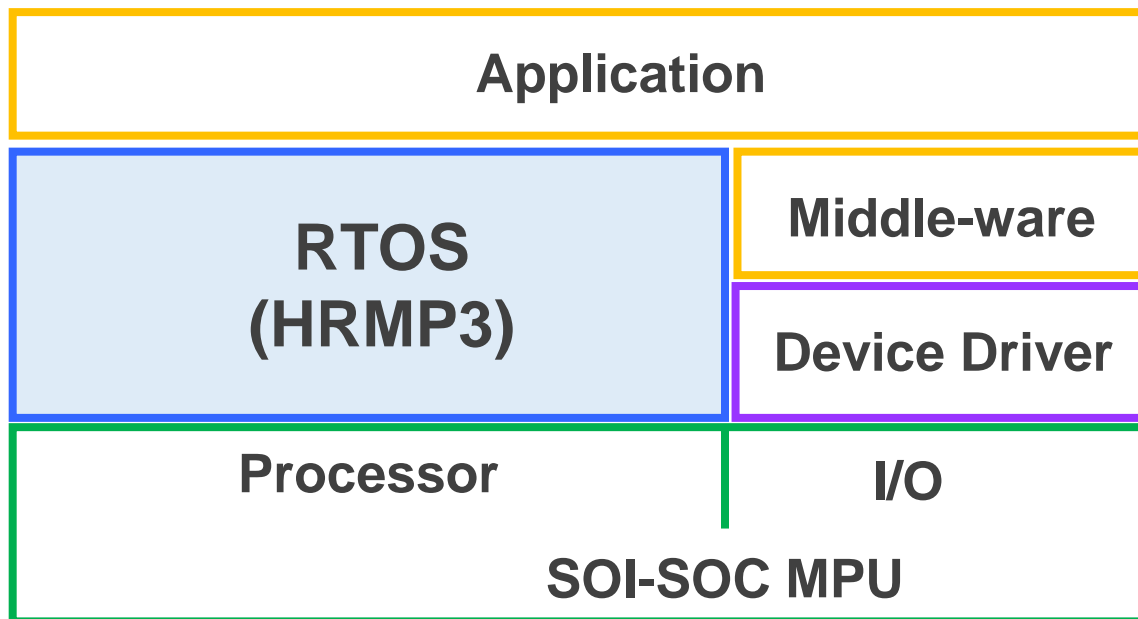
<https://www.renesas.com/jp/en/products/microcontrollers-microprocessors/rx-32-bit-performance-efficiency-mcus/rx-features>

- ❑ Evaluated score on the SOI-SOC MPU (Engineering model)


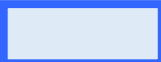

Device	Score [Coremark/MHz/Core]	
	CPU0	CPU1
HR5000S	1.54	-
SOI-SOC MPU	4.82	-
SOI-SOC MPU	2.61	2.6



- ❑ Realtime Operating System (RTOS) which is suitable for our MPU is under developing.
 - ❑ Base model is TOPPERS/HRP (High Reliable system Profile) kernel (HR5000S).
 - ❑ Beta-version has already released and built in the MPU (EM) for evaluation.
 - ❑ Evaluation combined RTOS with Printed Circuit Board has completed.



On-orbit demonstration under cinsideration

-  User needs to develop
-  We are developing
-  We provide sample programs

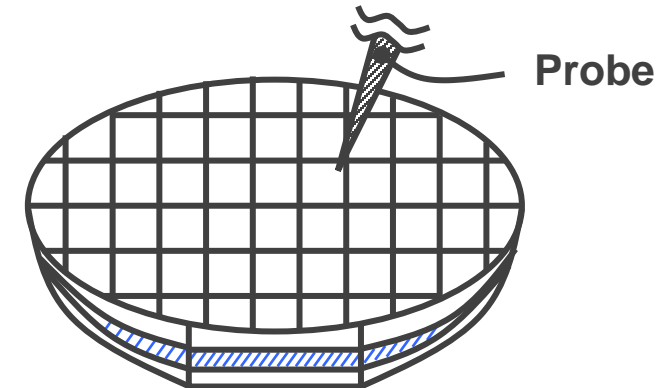
□ Function ✓ Completed

- Memory built-in self test (M-BIST) for static random-access memory (SRAM) region
- DC function test
- AC function test
- Loose function test
- SCAN test for distributed logic circuit (combinational logic & sequential logic)
- PLL function

Desired logic functions were validated

□ Performance ✓ Completed

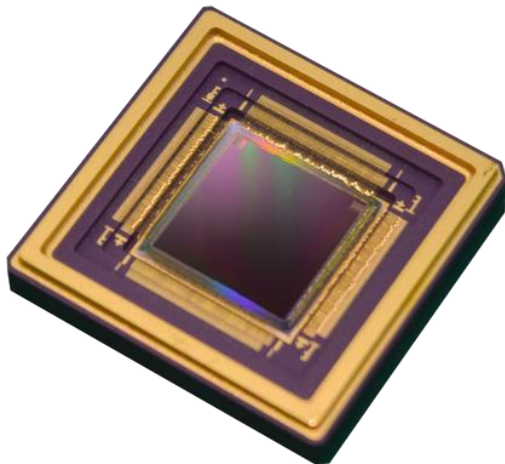
- SCAN test for critical path of distributed logic circuit
- IDDQ, IDDA



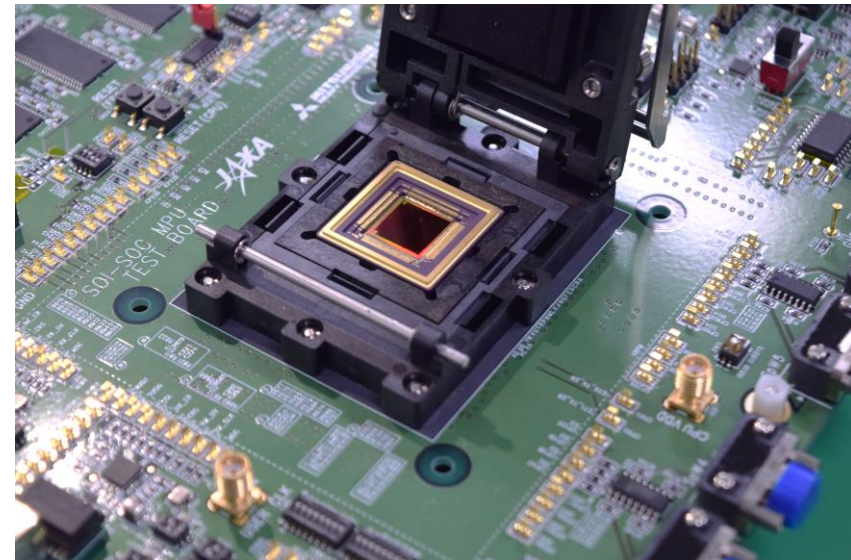
Operating frequency & power consumption were validated

- We've designed and manufactured printed circuit boards for evaluation test
 - Electronical evaluation (including operating performance)
 - Functional evaluation (including communicate with peripheral chip)
 - Quick-sort
 - CoreMark Score
 - Space Wire communication program

- Radiation test (SEE, TID)



Photograph of EM-chip assembled on a BGA package



Photograph of evaluation board

7. Evaluation (Brief summary of the test results)



□ Below table shows the test results of both electrical and radiation test

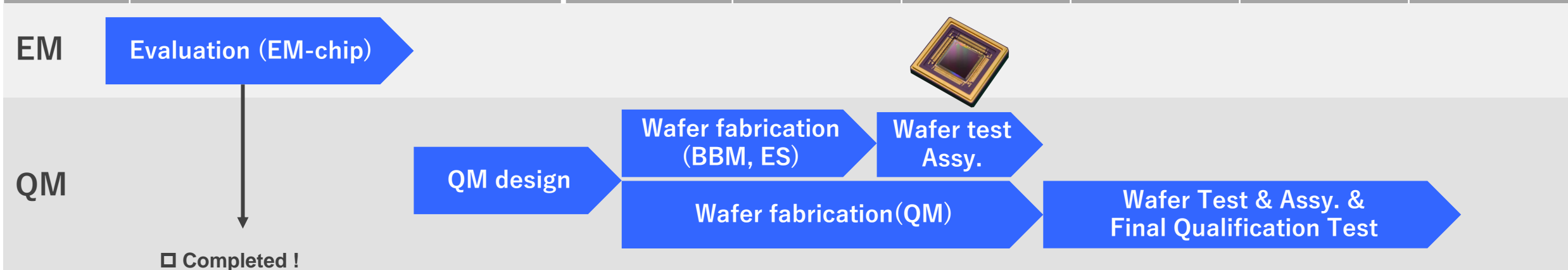
Evaluation	Result	Comment
Frequency	280 MHz (max.) @PVT=Typical	Benchmark program (CoreMark)
Performance [CoreMark@250MHz]	800 ~ 1200	Depending on the operating configuration
Power Consumption	0.787 W @PVT=Typical	CPU0: CoreMark CPU1: Space Wire
Radiation	<ul style="list-style-type: none">• SRAM w/ RHBD: 40 MeV/(mg/cm²)• SRAM w/ EDAC: 40 MeV(mg/cm²)• SEL: \geq 80 MeV/(mg/cm²) @ 125°C• EM-chip: \leq 100FIT	

8. Development schedule

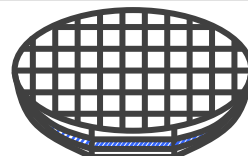


- ❑ Wafer process has been finished
- ❑ Wafer Test and assembly are on-going
- ❑ Final qualification test will start soon
- ❑ Development of this MPU will be finished until the middle of JFY 2023

Phase	~ JFY2021	JFY2022				JFY2023	
		4	7	10	1	4	7



- ❑ Completed !
- Wafer Electrical Test
- Board Electrical Test
- Radiation Test
- OS verification
- Preliminary Qualification Test



Thank you for your kind attention

URL of this MPU

<http://www.kenkai.jaxa.jp/eng/research/soisoc/soisoc.html>

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